



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

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## Product Summary

$V_{(BR)DSS}$	$R_{DS(ON)}$	Package	$I_D$ $T_A = +25^\circ\text{C}$
60V	$V_{GS} = 10\text{V}$	SOT-363	200mA

## Features

- N-MOSFET with ESD Gate Protection
- N-MOSFET with Low On-Resistance ( $R_{DS(ON)}$ )
- Low  $V_f$  Schottky Diode
- Low Static, Switching, and Conduction Losses
- Good Dynamic Performance
- Surface Mount Package Suited for Automated Assembly

## Description

The NK-NMSD200B01 improves the efficiency and reliability of DC-DC controllers used in Voltage Regulator Modules (VRM) and can support a continuous maximum current of 200mA. It features an ESD protected discrete N-MOSFET with low on-resistance and a discrete Schottky diode with low forward drop.

The device reduces component count, consumes less space, and minimizes parasitic losses. The component devices can be used as a part of a circuit or as a stand-alone discrete device.

## Applications

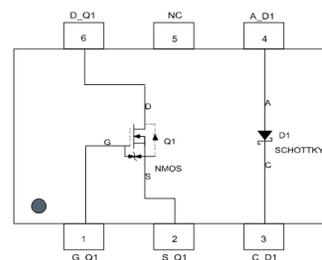
- Switching Voltage Regulators
- Power Management Applications

## Mechanical Data

- Case: SOT-363
- Case Material: Molded Plastic. "Green Molding" Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020D
- Terminal Connections: See Diagram
- Terminals: Finish - Matte Tin annealed over Alloy 42 Lead-Frame. Solderable per MIL-STD-202, Method 208 **Ⓔ**
- Weight: 0.006 grams (Approximate)



Top View



Pin Configuration

**Maximum Ratings** @  $T_A = 25^\circ\text{C}$  unless otherwise specified

Characteristic	Symbol	Value	Unit
Power Dissipation (Note 5)	$P_d$	200	mW
Output Current	$I_{out}$	200	mA

**Maximum Ratings** (@  $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

**Sub-Component Device: ESD Protected N-Channel MOSFET (Q1)**

Characteristic	Symbol	Value	Unit
Drain Source Voltage	$V_{DSS}$	60	V
Drain Gate Voltage (RGS <+ 1M $\Omega$ )	$V_{DGR}$	60	V
Gate Source Voltage	Continuous $V_{GSS}$	+/-20	V
Drain Current (Note 5)	Continuous ( $V_{gs}=10\text{V}$ ) $I_D$	200	mA

**Maximum Ratings** @  $T_A = 25^\circ\text{C}$  unless otherwise specified

**Sub-Component Device: Schottky Diode (D1)**

Characteristic	Symbol	Value	Unit
Peak Repetitive Reverse Voltage	$V_{RRM}$	40	V
Working Peak Reverse Voltage	$V_{RWM}$		
DC Blocking Voltage	$V_R$		
RMS Reverse Voltage	$V_{R(RMS)}$	28	V
Forward Continuous Current (Note 5)	$I_{FM}$	350	mA
Non-Repetitive Peak Forward Surge Current @ $t < 1.0$ s	$I_{FSM}$	1.5	A

**Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Junction Operation and Storage Temperature Range	$T_j, T_{stg}$	-55 to +150	$^\circ\text{C}$
Thermal Resistance, Junction to Ambient Air (Note 5) (Equivalent to one heated junction of N-MOSFET)	$R_{\theta JA}$	625	$^\circ\text{C/W}$

Note: 5. Device mounted on FR-4 PCB, 1 inch square, 2oz copper pad area.

**Electrical Characteristics** @  $T_A = 25^\circ\text{C}$  unless otherwise specified

**Sub-Component Device: ESD Protected N-Channel MOSFET (Q1)**

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 6)</b>						
Drain-Source Breakdown Voltage, $BV_{DSS}$	$V_{BR(DSS)}$	60	—	—	V	$V_{GS} = 0V, I_D = 10\mu A$
Zero Gate Voltage Drain Current (Drain Leakage Current)	$I_{DSS}$	—	—	1	$\mu A$	$V_{GS} = 0V, V_{DS} = 60V$
Gate Body Leakage Current, Forward	$I_{GSSF}$	—	—	10	$\mu A$	$V_{GS} = 20V, V_{DS} = 0V$
Gate Body Leakage Current, Reverse	$I_{GSSR}$	—	—	-10	$\mu A$	$V_{GS} = -20V, V_{DS} = 0V$
<b>ON CHARACTERISTICS (Note 6)</b>						
Gate Source Threshold Voltage (Control Supply Voltage)	$V_{GS(th)}$	1	1.6	2.5	V	$V_{DS} = V_{GS} = 10V, I_D = 0.25mA$
		1.1	1.8	3	V	$V_{DS} = V_{GS} = 10V, I_D = 1mA$
Static Drain-Source On-State Voltage	$V_{DS(on)}$	—	0.09	1.5	V	$V_{GS} = 5V, I_D = 50mA$
		—	0.62	1.25	V	$V_{GS} = 10V, I_D = 500mA$
Static Drain-Source On Resistance	$R_{DS(on)}$	—	1.6	3	$\Omega$	$V_{GS} = 5V, I_D = 50mA$
		—	1.5	2	$\Omega$	$V_{GS} = 10V, I_D = 500mA$
Forward Transconductance	$g_{FS}$	80	420	—	mS	$V_{DS} \geq 2 \cdot V_{DS(ON)}, I_D = 200mA$
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{iss}$	—	—	50	pF	$V_{DS} = 25V, V_{GS} = 0V, f = 1MHz$
Output Capacitance	$C_{oss}$	—	—	25	pF	
Reverse Transfer Capacitance	$C_{rss}$	—	—	5	pF	
<b>Switching Characteristics</b>						
Turn-On Delay Time	$t_{d(on)}$	—	—	20	ns	—
Turn-Off Delay Time	$t_{d(off)}$	—	—	40	ns	—
<b>Drain-Source (Body) Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward On-Voltage	$V_{SD}$	—	0.88	1.5	V	$V_{GS} = 0V, I_S = 300mA$

**Electrical Characteristics** @  $T_A = 25^\circ\text{C}$  unless otherwise specified

**Sub-Component Device: Schottky Barrier Diode (D1)**

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
Reverse Breakdown Voltage (Note 6)	$V_{(BR)R}$	40	—	—	V	$I_R = 10\mu A$
Forward Voltage Drop (Note 6)	$V_{FM}$	—	—	0.37	V	$I_F = 20mA$
		—	—	0.6		$I_F = 200mA$
Peak Reverse Current (Note 6)	$I_{RM}$	—	—	5	$\mu A$	$V_R = 30V$
Total Capacitance	$C_T$	—	39	—	pF	$V_R = 0V, f = 1.0MHz$
Reverse Recovery Time	$t_{rr}$	—	10	—	ns	$I_F = I_R = 30mA, I_{rr} = 0.1 \cdot I_R, R_L = 100\Omega$

Note: 6. Short duration pulse test used to minimize self-heating effect.

## Typical Characteristics

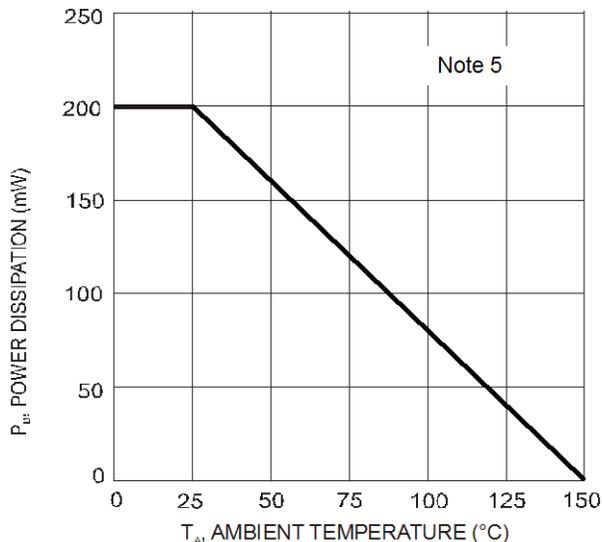


Fig. 1 Max Power Dissipation vs. Ambient Temperature

## Typical N-Channel Characteristics

Sub-Component Device: MOSFET-Q1 (ESD Protected)

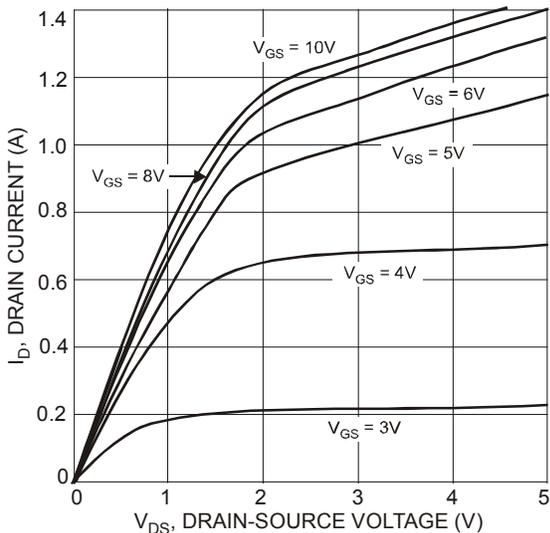


Fig. 2 Output Characteristics

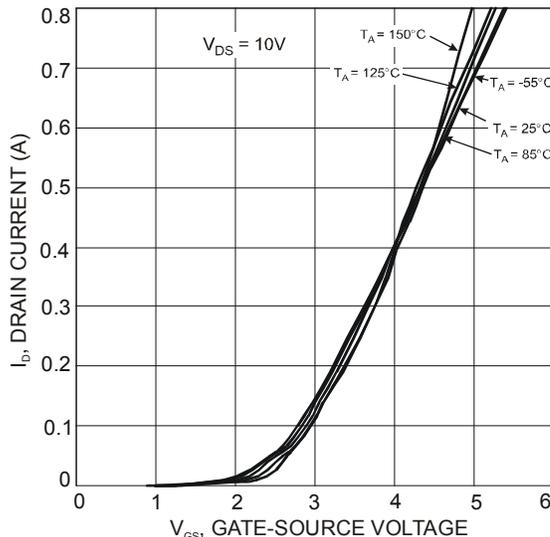


Fig. 3 Transfer Characteristics

**Typical N-Channel Characteristics** (cont.)

Sub-Component Device: MOSFET-Q1 (ESD Protected)

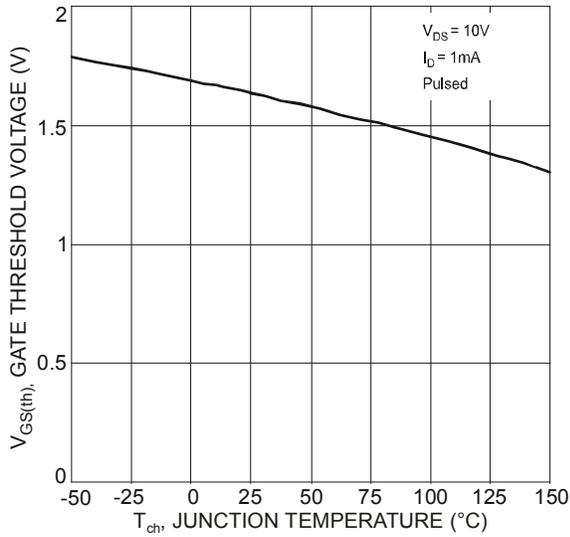


Fig. 4 Gate Threshold Voltage vs. Junction Temperature

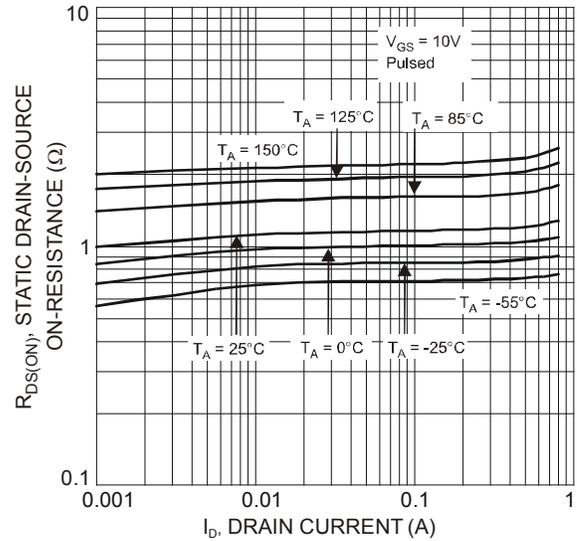


Fig. 5 Static Drain-Source On-Resistance vs. Drain Current

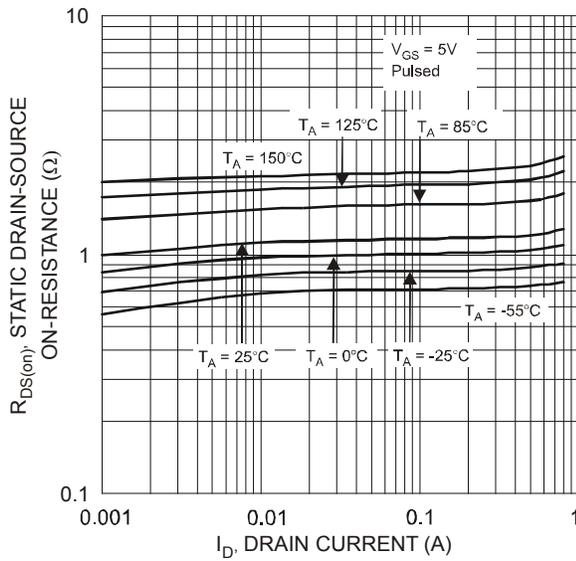


Fig. 6 Static Drain-Source On-Resistance vs. Drain Current

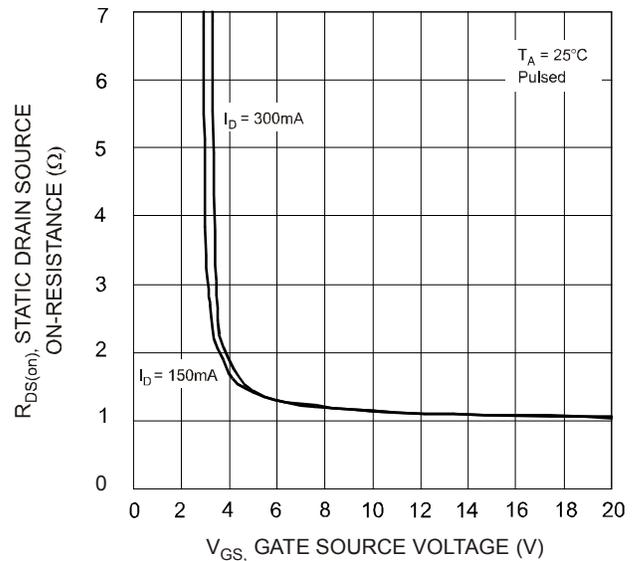


Fig. 7 Static Drain-Source On-Resistance vs. Gate-Source Voltage

**Typical N-Channel Characteristics** (cont.)

Sub-Component Device: MOSFET-Q1 (ESD Protected)

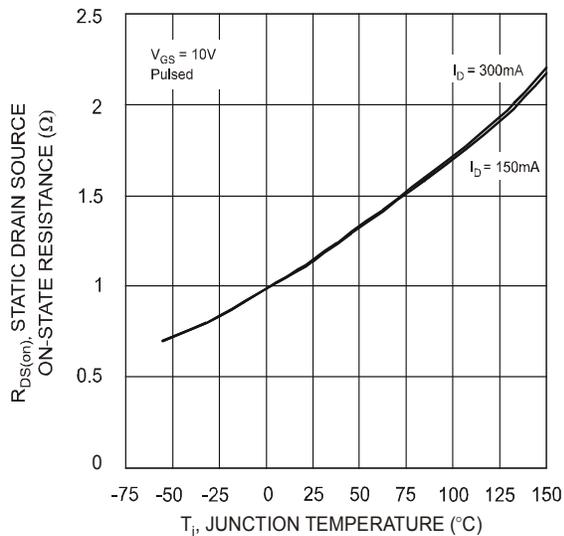


Fig. 8 Static Drain-Source On-State Resistance vs. Junction Temperature

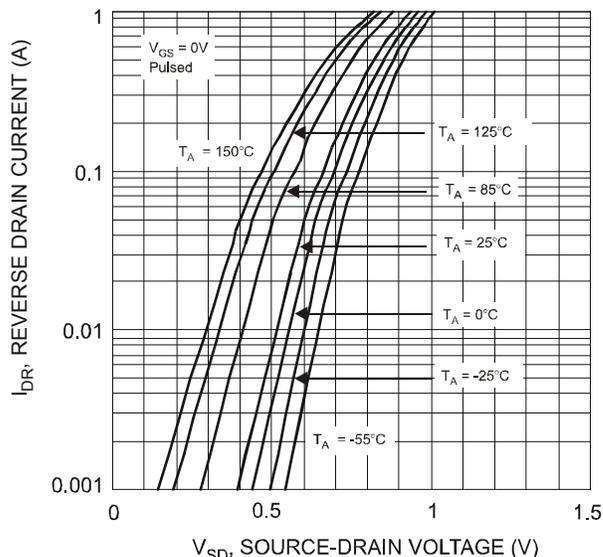


Fig. 9 Reverse Drain Current vs. Source-Drain Voltage

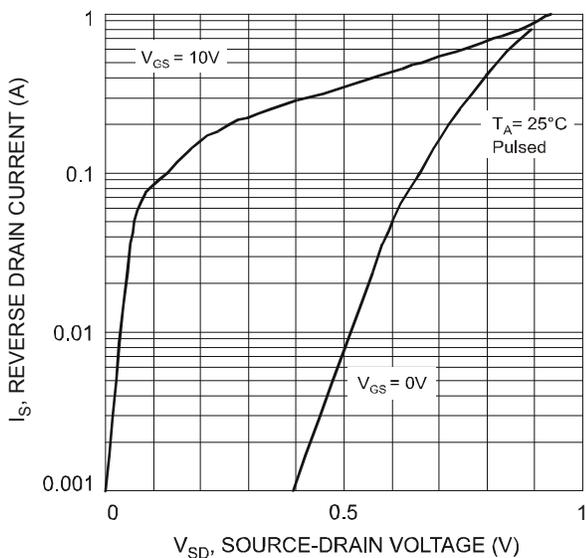


Fig. 10 Reverse Drain Current vs. Body Diode Forward Voltage

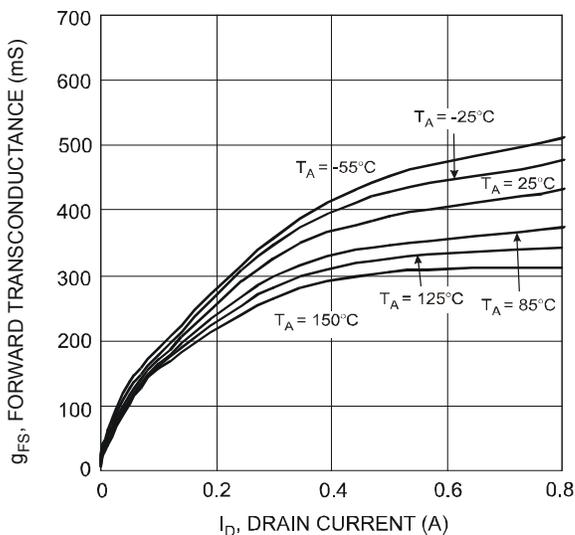


Fig. 11 Forward Transconductance vs. Drain Current ( $V_{DS} > I_D * R_{DS(ON)}$ )

## Typical Characteristics

Sub-Component Device: Schottky Barrier Diode (D1)

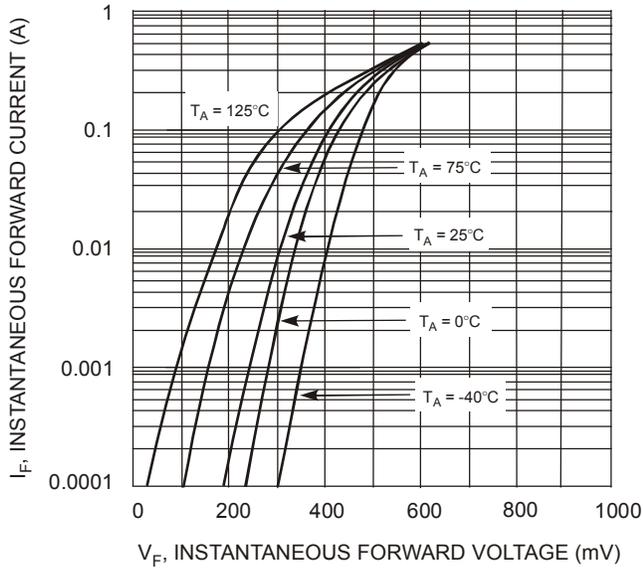


Fig. 12 Forward Characteristics

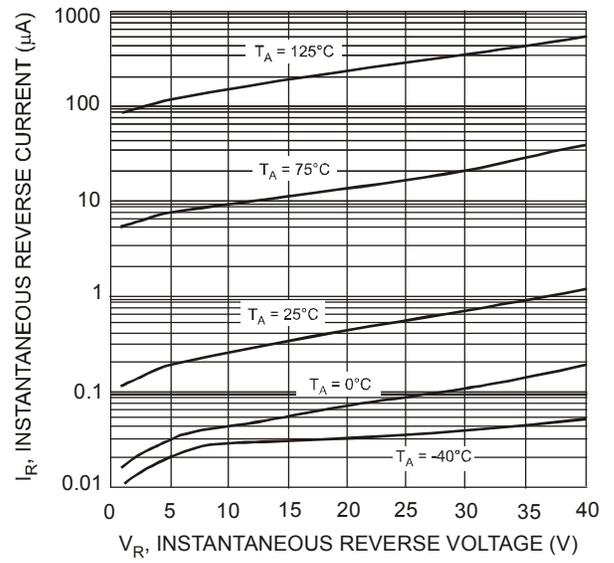


Fig. 13 Reverse Characteristics

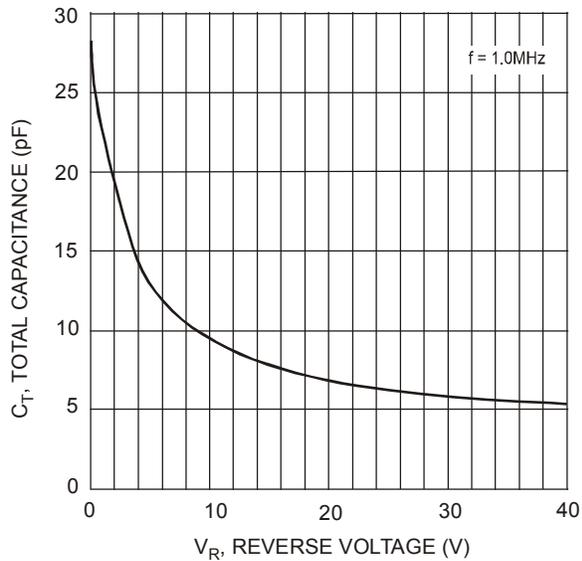
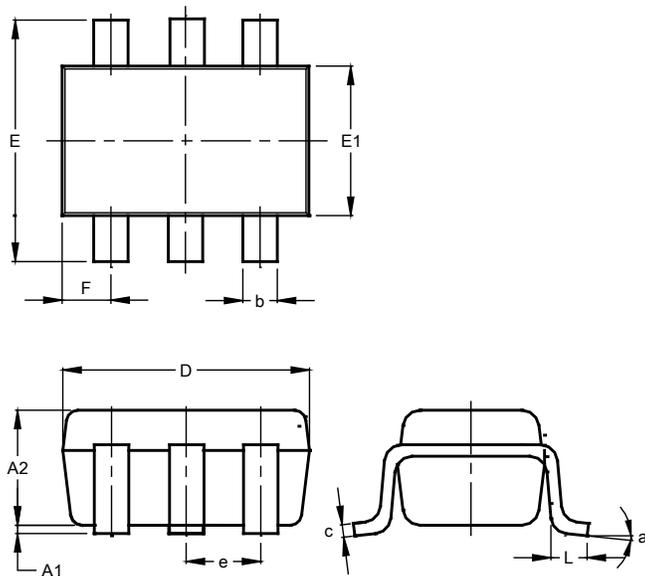


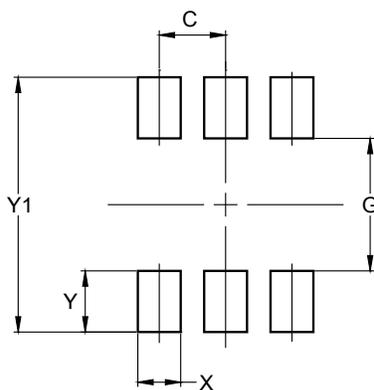
Fig. 14 Total Capacitance vs. Reverse Voltage

## Package Outline Dimensions

**SOT363**


SOT363			
Dim	Min	Max	Typ
A1	0.00	0.10	0.05
A2	0.90	1.00	0.95
b	0.10	0.30	0.25
c	0.10	0.22	0.11
D	1.80	2.20	2.15
E	2.00	2.20	2.10
E1	1.15	1.35	1.30
e	0.650 BSC		
F	0.40	0.45	0.425
L	0.25	0.40	0.30
a	0°	8°	--
All Dimensions in mm			

## Suggested Pad Layout

**SOT363**


Dimensions	Value (in mm)
C	0.650
G	1.300
X	0.420
Y	0.600
Y1	2.500